

Product Change Notification: CAAN-02HDKP333

Date:

05-Feb-2025

Product Category:

32-Bit Microcontrollers

Notification Subject:

CCB 7395 Final Notice: Qualification of ANAP as an additional assembly site for ATSAM3U1EB-AU catalog part number (CPN) available in 144L LQFP (20x20x1.4mm) package.

Affected CPNs:

CAAN-02HDKP333_Affected_CPN_02052025.pdf CAAN-02HDKP333_Affected_CPN_02052025.csv

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of ANAP as an additional assembly site for ATSAM3U1EB-AU catalog part number (CPN) available in 144L LQFP (20x20x1.4mm) package.

Pre and Post Summary Changes:

	Pre Change	Post Change	
Assembly Site	ATX Semiconductor (Shanghai) Co. Ltd (ASSH)	ATX Semiconductor (Shanghai) Co. Ltd (ASSH)	Amkor Technology Philippine (P1/P2), INC. (ANAP)
Wire Material	Au	Au	AuPd

Die Attach Material	2288A	2288A	3230
Molding Compound Material	CEL-9200THF	CEL-9200THF	G631HQ
Lead-Frame Material	C7025	C7025	C194
Lead-Frame Lead-Lock	None	None	Locking Lug
Lead-Frame Design	See Pre and Post Chang	e Summary for Comparis	son

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance by qualifying ANAP as an additional

assembly site.

Change Implementation Status: In Progress

Estimated First Ship Date: 31 March 2025 (date code: 2514)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may

receive pre and post change parts.

Timetable Summary:

	Febr	uary 2	2025			Marc	:h 202	<u>!</u> 5		
Work Week	05	06	07	08	09	10	11	12	13	14
Qual Report Availability		Х								
Final PCN Issue Date		Х								
Estimated Implementation Date										Х

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as

PCN_#_Qual_Report.

Revision History: February 05, 2025: Issued final notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CAAN-02HDKP333 Qual Report.pdf
PCN_CAAN-02HDKP333 Pre and Post Change Summary.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to <u>change your PCN profile, including opt out,</u> please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

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Affected Catalog Part Numbers (CPN)
ATSAM3U1EB-AU
Date: Wednesday, February 5, 2025

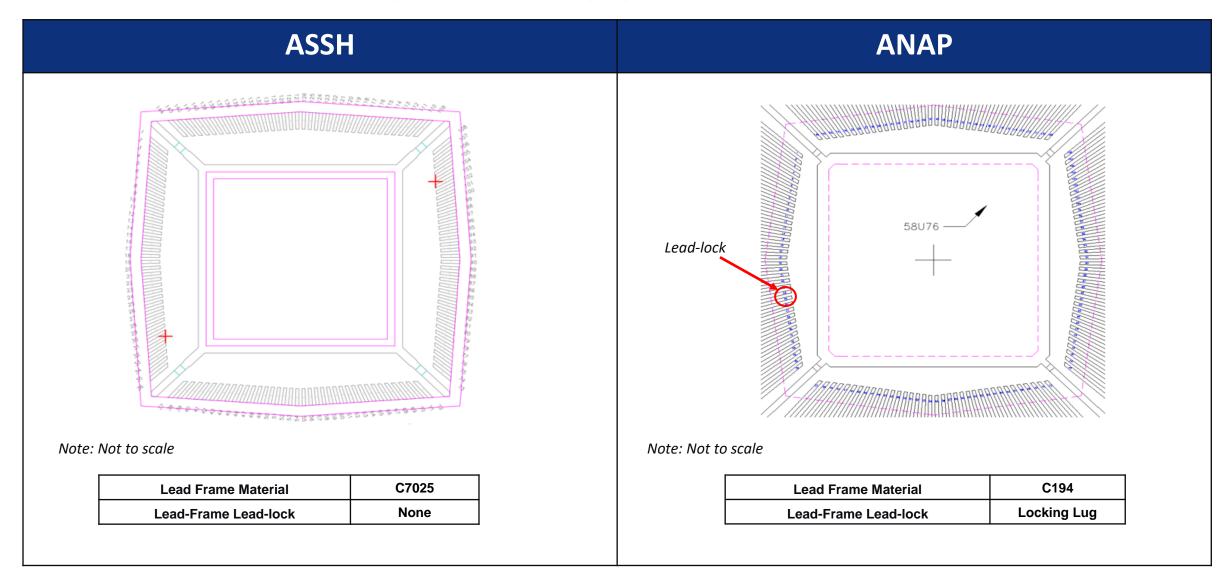
CCB 7395 Pre and Post Change Summary PCN #: CAAN-02HDKP333



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LEAD FRAME COMPARISON







QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN #: CAAN-02HDKP333

Date: September 24, 2021

Qualification of ANAP as an additional assembly site for ATSAM3U1EB-AU catalog part number (CPN) available in 144L LQFP (20x20x1.4mm) package will qualify by similarity (QBS). This is Q100 Grade 1 qualification.



Purpose: Qualification of ANAP as an additional assembly site for ATSAM3U1EB-AU catalog part number (CPN) available in 144L LQFP (20x20x1.4mm) package

will qualify by similarity (QBS). This is Q100 Grade 1 qualification.

CCB No: 4443 and 7395

	Assembly site	ANAP
	BD Number	BDM-002758A
	MP Code (MPC)	58U94YH8XC02
	Part Number (CPN)	AT32UC3C0512C-ALZR
Misc.	MSL information	MSL-3 @260C
	Assembly Shipping Media (T/R, Tube/Tray)	T/R
	Base Quantity Multiple (BQM)	800 units
	Reliability Site	MPHIL
	Paddle size	276x276 mils
	Material	C194
	DAP Surface Prep	Double Ring Ag
Land France	Process	STAMPED
<u>Lead-Frame</u>	Lead-lock	Yes
	Part Number	101384548
	Lead Plating	Matte Tin
	Strip Density	UDLF
Bond Wire	Material	AuPd
Dia Aurah	Part Number	3230
Die Attach	Conductive	Yes
<u>MC</u>	Part Number	G631HQ
	PKG Type	LQFP
<u>PKG</u>	Pin/Ball Count	144
	PKG width/size	20x20x1.4mm



Manufacturing Information

Assembly Lot No.
ANAP213300097.000
ANAP213300098.000
ANAP213300099.000

Result	V	Pass	Fail	

58U94YH8XC02 using UDLF LF#101384548 and mold compound G631HQ with 0.15um wafer tech. in 144L LQFP 20x20x1.4mm from ANAP pass reliability stress tests per QCI-39000 conducted at MPHL rel lab. This package is qualified Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

	PACKAGE QUALIFI	CATIO	NRE	PORT	Γ	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests	Electrical Test :25°C Magnum	JESD22- A113,	231 per lot	Lot 1 0/231	Pass	Good Devices
(At MSL Level 3)		JIP/ IPC/JEDE C J-STD-		Lot 2 0/231	Pass	
		020E		Lot 3 0/231	Pass	
	Bake 150°C, 24 hrs System: HERAEUS		231 per lot			
	Moisture Soak 192h(30°C/60%RH) System: Climats Excal 5423-HE		231 per lot			
	Reflow 3x Convection-Reflow 265°C max System: Mancorp CR.5000F		231 per lot	Lot 1 0/231	Pass	
				Lot 2 0/231	Pass	
				Lot 3 0/231	Pass	
	Electrical Test :25°C Magnum		231 per lot	Lot 1 0/231	Pass	
				Lot 2 0/231	Pass	
				Lot 3 0/231	Pass	

	PACKAGE QUALIFIC	ATION	IREF	PORT	1	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
UNBIASED HAST	Stress Condition: (Standard) + 130°C, 85%RH, 96 hrs. System: HIRAYAMA HASTEST PC-422R8	JESD22- A118	77 units per lot		Pass Pass	Parts had been pre-conditioned at 260°C
	Electrical Test: 25°C System: Magnum			Lot 3 0/77	Pass	
HAST	Stress Condition: (Standard) 130°C, 85%RH, 96 hrs. VOLTS=5.5V System: HIRAYAMA HASTEST PC-422R8	JESD22- A110	77 units per lot		Pass	
	Electrical Test: 25°C /130°C System: Magnum			Lot 3 0/77	Pass	

	PACKAGE QUAI	LIFICAT	FION F	REPORT	Γ	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temp Cycle	Stress Condition: (Standard) -65°C to +150°C, 500 Cycles System: Votsch VTS²7012 Electrical Test: 130°C System: Magnum	JESD22- A104	77 units per lot	Lot 1 0/77 Lot 2 0/77 Lot 3 0/77	Pass Pass Pass	Parts had been pre- conditioned at 260°C
	Bond Strength: Wire Pull (> 1.75 grams) Bond Shear (> 12.6 grams) System: Dage		5 units, 30 bonds per lot	Lot 1 0/30 Lot 2 0/30 Lot 3 0/30	Pass Pass Pass	
High Temperature Storage Life	Stress Condition: Bake 175°C, 500 hrs System: HERAEUS Electrical Test: 25°C/130°C System: Magnum	JESD22- A103	45 units per lot	Lot 1 0/45	Pass	

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Bond Strength	System: Dage Wire Pull (> 1.75 grams) Bond Shear (>12.6 grams)		5 units, 30 bonds per lot	Lot 1 0/30	Pass	
	Bond Onedi (2 12.0 gramo)		periot	Lot 2 0/30	Pass	
				Lot 3 0/30	Pass	
Solderability	Bake: Temp 155°C,4Hrs System: Oven Solder Bath: Temp.245°C Solder material: SAC305 Visual Inspection: External Visual Inspection	J-STD-002D	22 units from 1 lot	0/22	Pass	
Physical Dimension	Physical Dimension, 30 units from 3 lots	JESD22 -B100/B108	22 units	Lot 1 0/22	Pass	
Dimension		2 100/2 100	per lot	Lot 2 0/22	Pass	
				Lot 3 0/22	Pass	